PCN Number:	20230215000.1				PCN Date: February 16, 2023			
Title:Qualification of additional Fab sites (CFAB & DL-LIN) using qualified Process Technology and additional Assembly sites options for select devices								
Customer Contact:				Quality Services		ality Services		
Proposed 1st Ship Date	e: May	/ 17, 202	23		Sample re accepted	-	Маг	r 18, 2023*
*Sample requests re	ceived af	ter Mar	18, 20	23 wi				
Change Type:								
Assembly Site	\triangleright	Assei	mbly Pr	ocess		Asse	embly	y Materials
Design		Elect	rical Sp	ecificat	tion	Mec	hanio	cal Specification
Test Site		_			abeling	_	: Prod	
Wafer Bump Site				Mater				Imp Process
Wafer Fab Site				1aterial			er Fa	b Process
				r chang				
Description of Chang			PCN	Detai	IS			
Qualification of addition additional Assembly sit		for the I		,	in the prod		ed se	ction below.
			C					
Current Fab Site	rocess	Wa [:] Diam			litional b Site	Proce	ss	Wafer Diameter
				CFAE	3			
DL-LIN I	BC3S	150r	mm	DL-L	IN	LBC3	S	200mm
Construction difference Group 3 Devices (CF site):			dditior	nal Fab	sites & T	IPI as ad	ditio	onal Assembly
				L	.EN	Т	IPI	
M	old Compo	und	S	SID#0011G60007 4222198		8		
Bond	wire comp diameter			Au, 1.0 mil		Cu,	1.0 n	nil
Mo	unt Compo		S	SID#0003C10332 4207123		3		
Group 5 Devices (CF	AB as add	litional	Fab sit	e, TI I	Malaysia a	s additio	nal A	ssembly site):
			TAI		Ν	1LA		
Bond wire composition, diameter		Au, 0.96 mil Cu, 0.96 mil **		il **				
** - Applies to only TLC2274MDR Group 6 Devices (CFAB as additional Fab site, CDAT as additional Assembly site):								
Group 6 Devices (CF	AB as add	litional	rad sit				DAT	bly site):
Mold Compound		TFME SID #R-13				2		
Mold Compound Bond wire composition,						22198 1.0 n		
dia meter			Au, 1.0 mil					
Mc	unt Compo	ound		SID	# A-03	420)712	3
Qual details are provid	ed in the C)ual Data	a Sectio	on.				
Reason for Change:								

These changes are part of our multiyear plan to transition products from our 150-milimeter factories to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Impact on Environmental Ratings

Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.

RoHS	REACH	Green Status	IEC 62474
🛛 No Change	🛛 No Change	🛛 No Change	🛛 No Change

Changes to product identification resulting from this PCN:

Fab Site Information:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
DL-LIN	DLN	USA	Dallas
CFAB	CU3	CHN	Chengdu
DL-LIN	DLN	USA	Dallas

Assembly Site Information:

Assembly Site	Assembly Site Origin (22L)	Assembly Country Code (23L)	Assembly City
TAI	TAI	TWN	Chung Ho, New Taipei City
LEN	LIN	TWN	Taichung
TFME	NFM	CHN	Economic Development Zone
CDAT	CDA	CHN	Chengdu
TI Malaysia	MLA	MYS	KUALA LUMPUR
TIPI	PHI	PHL	Baguio City

Sample product shipping label (not actual product label)



Product Affected:						
Group 1 Device li	Group 1 Device list (DFAB8 & CFAB as additional Fab sites only)					
TLC074IN	TLC083IDGQ	TLV2475AIDR	TPS3705-50DGN			
TLC082CP	TLV2475CDR	TPS3705-30DGN	TPS3705-33DGNR			
TLC075AID	TLC083CDGQR	TPS3705-33DGN	TPS3705-50DGNR			
TLV2370IP						

Group 2 Device list (CFAB & DFAB8 as additional Fab sites & TI Malaysia as additional Assembly site)

TLC074CPWP	TLC074CPWPR	TLV2474AIPWP	TLV2474IPWPR
TLC074IPWP	TLV2474CPWP	TLV2474CPWPR	TLV2474AIPWPR
TLC075IPWP			

Group 3 Device list (CFAB & DFAB8 as additional Fab sites & TIPI as additional Assembly site)

TLV2370IDBVR	TLV2370IDBVT
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Group 4 Device list (CFAB as additional Fab site)

TLV271IP	TLC2272ACP	TLC2252CPWR	TLC2252AIPWR
TLC2252CP	TLC2272CPW	TLC2272ACPW	TLC2272ACPWR
TLC2272CP	TLC2272IPW	TLC2272CPSR	TRS3253EIRSMR
TLC2272IP	TLV2252AIP	TLC2272CPWR	
TLV2371IP	MAX3232EIDW R	TRS3232ECDWR	
MAX3232ECDW R	SN104800PSR	TLC2272IPW R	

Group 5 Device list (CFAB as additional Fab site, TI Malaysia as additional Assembly site)					
TLC084IPWP	TLC084CPWPR	TLC084AIPWP	TLC084AIPWPR		
TLC2274MDR	TLC084IPWPR	TLC085AIPWP			

Group 6 Device list (CFAB as additional Fab site, CDAT as additional Assembly site)

TLV271CDBVR TLV271CDBVT

For alternate parts with similar or improved performance, please visit the product page on $\underline{\text{TI.com}}$



Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: TLV2401QDBVRQ1	QBS Process Reference: MAX3243IPWG4DL
HAST	Biased HAST, 130C/85%RH	96 Hours	3/231/0	3/231/0
AC	Autoclave 121C	96 Hours	3/231/0	3/231/0
тс	Temperature Cycle, - 65/150C	500 Cycles	3/231/0	3/231/0
HTSL	High Temp Storage Bake 150C	1000 Hours	-	3/231/0
HTSL	High Temp Storage Bake 175C	500 Hours	3/135/0	-
HTOL	Life Test, 150C	408 Hours	3/231/0	3/231/0
ELFR	Early Life Failure Rate, 125C	48 Hours	-	3/2400/0
HBM	ESD - HBM - Q100	500 V	1/3/0	-
CDM	ESD - CDM - Q100	1500 V	1/3/0	-
LU	Latch-up	(per JESD78)	1/6/0	-
ED	Electrical Characterization	Per Datasheet parameters	3/90/0	-

- QBS: Qual By Similarity

- Qual Device TLV2401QDBVRQ1 is qualified at LEVEL1-260C

A1 (PC): Preconditioning:

Performed for THB, Biased HAST, AC, uHAST, TC & PTC samples, as applicable.

Ambient Operating Temperature by Automotive Grade Level:

Grade 0 (or E): -40°C to +150°C Grade 1 (or Q): -40°C to +125°C Grade 2 (or T): -40°C to +105°C Grade 3 (or I): -40°C to +85°C

E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level):

Room/Hot/Cold: HTOL, ED Room/Hot: THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU Room: AC/uHAST



Qualification Report

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: <u>TLV3401IDBVT</u>	QBS Product Reference : <u>TLV2241D</u>	QBS Package Reference : TPS76933DBVR
AC	Autoclave 121C	96 Hours	-	-	3/231/0
ED	Electrical Characterization	Per Datasheet Parameters	1/Pass	-	-
HAST	Biased HAST, 110C/85%RH	96 Hours	-	-	3/231/0
HTOL	Life Test, 155C	240 Hours	-	1/77/0	-
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	-	3/231/0
HBM	ESD-HBM	2000 V	1/3/0	-	
TC	Temperature Cycle, -65/150C	500 Cycles	-	-	3/231/0
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	1/Pass	-	-
MQ	Test MQ	(per specification)	Pass	-	-
YLD	Yield Evaluation	(per mfg. Site specification)	Pass	-	-

- QBS: Qual By Similarity

- Qual Device TLV3401IDBVT is qualified at LEVEL1-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- Hours
-

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status: Qualified Pb-Free(SMT) and Green

TI Qualification ID: 20181113-127568

TEXAS	TI Information
INSTRUMENTS	Selective Disclosure

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed QBS Pack QBS Packad Qual Device: TLV9061IDBVR Reference: TPS76933DBVR (PHI) Reference Test Name / Condition Duration Туре TLV9061IDBVR (Matte <u>Sn)</u> FD Electrical Characterization, side by side Per Datasheet Parameters Pass 3/15/0 FI AM Flammability (UL 94V-0) Flammability (UL-1694) Biased HAST, 130C/85%RH 3/15/0 FLAM 96 Hours 3/231/0 HAST Life Test, 150C 300 Hours HTOL 3/231/0 HTSL High Temp Storage Bake 170C 3/231/0 420 Hours LI Lead Fatigue Leads 3/54/0 Ш Lead Pull Leads 3/54/0 MISC Salt Atmosphere 3/66/0 (per mfg. Site specification) (per mechanical drawing) MQ Manufacturability (Assembly) Pass 3/15/0 PD Physical Dimensions PKG 3/54/0 Lead Finish Adhesion Leads Pb Free SD Solderability 3/66/0 TC Temperature Cycle, -65/150C 500 Cycles 3/231/0 UHAST Unbiased HAST 130C/85%RH 96 Hours 3/231/0 VM Visual / Mechanical (per mfg. Site specification) 3/984/0 WBP Bond Pull Wires 3/228/0 Ball Bond Shear WBS Wires 3/228/0

QBS: Qual By Similarity

- Qual Device TLV9061IDBVR is qualified at LEVEL1-260C - Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours - The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: 20200211-132947



Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: TLC2264AQPWRQ1	Qual Device: TLC2264AIDRCT	QBS Process Reference: CD3301RHHR	QBS Package Reference: TLV9064QPWRQ1
HTOL	Life Test, 150C	300 Hours	1/3/0	-	3/231/0	-
HTSL	High Temp Storage Bake 170C	420 Hours	-	-	3/231/0	1/45/0
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	3/231/0	-
AC	Autoclave 121C	96 Hours	-	-	3/231/0	3/231/0
TC	Temperature Cycle, -65/150C	500 Cycles	-	-	3/231/0	3/231/0
HBM	ESD - HBM	2000 V	1/3/0	-	1/3/0	-
CDM	ESD - CDM	750 V	1/3/0		1/3/0	-
LU	Latch-up	(per JESD78)	1/6/0	-	1/6/0	-
ED	Electrical Characterization	Per Datasheet Parameters	1/30/0	-	1/30/0	-
MQ	Assembly MQ	Per Site Specifications	Pass	Pass	Pass	Pass

- QBS: Qual By Similarity - Qual Device TLC2264AQPWRQ1is qualified at LEVEL1-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent HTSL options based HAST, THE HABT, HA

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/ Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: 20200903-135990

TEXAS INSTRUMENTS

TI Information Selective Disclosure

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

QBS Process Reference: Qual Device: TLV2464CPWR QBS Package Reference: TPS2042BD QBS Package Reference TPS2419DR Test Name / Condition Duration Type CD3301RHHR HTOL Life Test, 150C 300 Hours 3/231/0 High Temp Storage Bake 170C Biased HAST, 130C/85%RH HTSI 420 Hours 3/231/0 3/231/0 3/231/0 96 Hours HAST 3/231/0 3/231/0 Autoclave 121C 3/231/0 3/231/0 96 Hours 3/231/0 AC ТС Temperature Cycle, -65/150C 500 Cycles 3/231/0 3/231/0 3/231/0 ESD - HBM HBM 4000 V 1/3/0 1/3/0 CDM ESD - CDM 1000 V 1/3/0 1/3/0 LU Latch-up (per JESD78) 1/6/0 1/6/0 Per Datasheet Parameters ED Electrical Characterization 1/30/0 1/30/0 MQ Assembly MQ Per Site Specifications Pass Pass Pass Pass

QBS: Qual By Similarity

Qual Device TLV2464CPWR is qualified at LEVEL1-260C

- Qual Device TL2/244C/FWR is qualified at LEVEL1-260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles
Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: 20210308-139022



Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: 1P8T245NSR	Qual Device: AD \$900E	Qual Device: PCM1801U	Qual Device: SN65HVD1781DR	Qual Device: TCA9546ADR	Qual Device: TCA9546ADR_RLF	Qual Device: TL494IDR
AC	Autoclave 121C	96 Hours	3/231/0	-	3/231/0	-	3/231/0	3/231/0	-
FLAM	Flammability (UL 94V-0)	-	-	-	-	-	3/15/0	3/15/0	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	-	-	-	-	3/231/0
HTSL	High Temp Storage Bake 170C	420 Hours	3/231/0	-	3/231/0	-	3/231/0	3/231/0	-
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	Pass	Pass	Pass	Pass	Pass	Pass	-
тс	Temperature Cycle, - 65/150C	500 Cycles	3/231/0	3/222/0	3/231/0	3/231/0	3/231/0	3/231/0	-
TC- BP	Post TC Bond Pull	Wires	-	-	-	3/90/0	3/162/0	3/90/0	-

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: TLC320AD77CDBR	Qual Device: TP \$2074DB	Qual Device: TPS2101D	Qual Device: TPS2214ADB	Qual Device: TSS721AD	Qual Device: UC27131D	QBS Package Reference: ULQ2003AQDRQ1_STDLF
AC	Autoclave 121C	96 Hours	3/231/0	3/231/0	-	3/231/0	-	-	3/231/0
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	-	-	-	-	3/231/0
HTOL	Life Test, 150C	408 Hours	-	-	-	-	-	-	3/231/0
HTSL	High Temp Storage Bake 150C	1000 Hours	-	-	-	-	-	-	1/45/0
HTSL	High Temp Storage Bake 170C	420 Hours	3/231/0	3/231/0	-	3/231/0	-	-	-
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	Pass	Pass	Pass	Pass	Pass	Pass	-
MQ	Manufacturability (Auto Assembly)	(per automotive requirements)	-	-	-	-	-	-	Pass
TC	Temperature Cycle, - 65/150C	500 Cycles	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0	-	3/231/0
TC- BP	Post TC Bond Pull	Wires	-	-	-	-	-	-	1/30/0

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
 The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: 20141019-109101, 20140520-104903 (QBS)

For questions regarding this notice, e-mails can be sent to the contact below or your local Field Sales Representative.

Location	E-Mail				
WW Change Management Team	PCN ww admin team@list.ti.com				

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